

Customer Profile

A manufacturer of precision test equipment for use in the semiconductor industry.

The Challenge

Front Opening Unified Pods, or "FOUPs" are specialized devices that stack silicon wafers allowing them to be transported safely around a semiconductor manufacturer's facility. Before being shipped to end-users, FOUPs must be tested for conformity to strict tolerances. One Baumer customer makes the machine that profiles the interior of the FOUP.

This customer requires five OADM sensors for every machine: two for measuring the interior contours of the FOUP's dividers; one for measuring height; and two more for measuring outside contours.

CAD drawing (see figure 1) shows the two OADM sensors used to profile the interior.

The Solution

OADM 1316475/S35A

Product Features

- 50-350 mm sensing distance
- Resolution down to 10 micrometers
- 4-20 mA or 0-10 V output
- Teachable measuring range
- <900 microsecond response time

Benefits to the Customer

- Self-contained: compact and easy to install
- Color independent: changing targets reliably measured
- High resolution: very small changes are easy to measure
- Fast response time: faster throughput in testing

Market Opportunities

- Semicon, wafer handling
- Automotive, parts production
- Electronic assembly, checking parts for correct installation
- Medical, inspection of medical tools and instruments

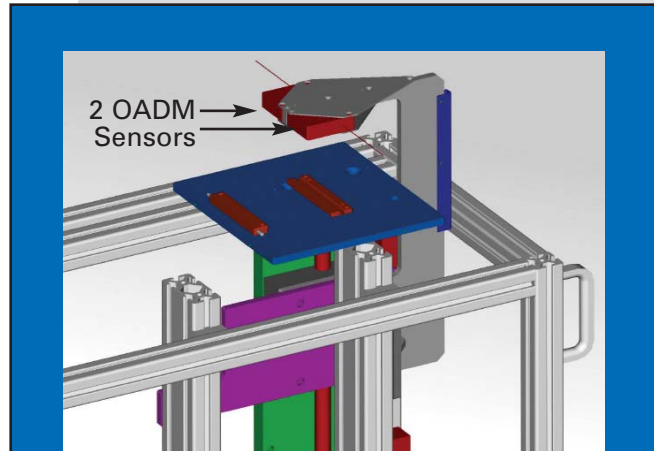


FIGURE 1



FIGURE 2

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